

FIG. 1

Fig. 1 is a schematic diagram of a device for measuring the thickness of a material. The device consists of a base 12 with a central opening 13. A probe 14 is inserted into the opening, and a measuring head 15 is positioned at the bottom of the opening. The material being measured is divided into three regions: C (left), D (center, hatched), and E (right). The regions are numbered 4, 5, and 6 respectively.

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graph LR
    15((15)) --> 16[Transmitter Receiver Assembly]
    16 --> 18[Data Storage]
    18 --> 10[Computer]
  
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**FIG. 3**

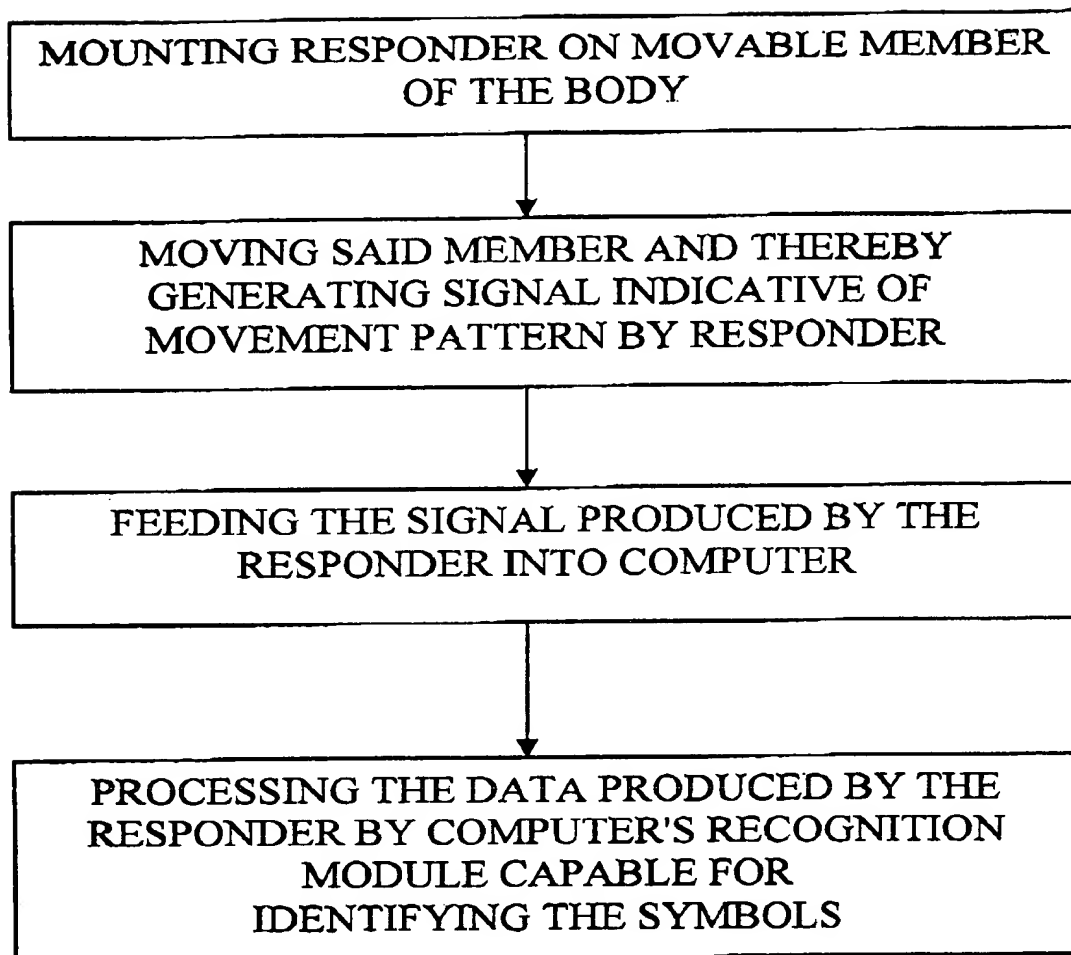


FIG.4